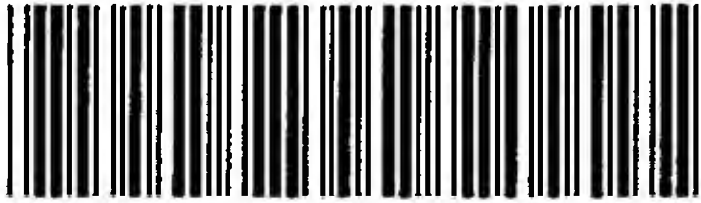


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,724	KANG ET AL.	
	Examiner	Art Unit	
	Russell M. Kobert	2829	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference Search History Printout		11/26/2005	RK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - see search history printout(s)	11/23/2005	RK
324/765,769,158.1; class 716; class 438; class 702 (text search only - see search history printout)	11/23/2005	RK
Internet search - search string "wafer and test and (stress-induced degradation or SLIC) and pdf"	11/23/2005	RK
Internet search - search string "(stress-induced degradation or SLIC) and ratio and pdf"	11/23/2005	RK